N-Channel 650V (D-S) Power MOSFET

PRODUCT SUMMARY				
V_{DS} (V) at T_J max.	650			
R _{DS(on)} max. at 25 °C (Ω)	V _{GS} = 10 V 1.1			
Q _g max. (nC)	25			
Q _{gs} (nC)	2.0			
Q _{gd} (nC)	2.7			
Configuration	Single			

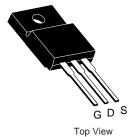
FEATURES

- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (Ciss)
- · Reduced switching and conduction losses
- Ultra low gate charge (Q_q)
- Avalanche energy rated (UIS)

APPLICATIONS

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
 - High-intensity discharge (HID) - Fluorescent ballast lighting
- Industrial

TO-220 FULLPAK



GC N-Channel MOSFET

PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V _{DS}	650	V
Gate-Source Voltage			V _{GS}	± 30	v
Continuous Drain Current (T ₁ = 150 °C)	V _{GS} at 10 V	T _C = 25 °C T _C = 100 °C	L	7.0	A
Continuous Drain Current $(T_j = 150 \text{ C})$		T _C = 100 °C	ID	5.6	
Pulsed Drain Current ^a			I _{DM}	28	
Linear Derating Factor				1.67/1.5/0.3	W/°C
Single Pulse Avalanche Energy b			E _{AS}	86	mJ
Maximum Power Dissipation			PD	83/83/31	W
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C
Drain-Source Voltage Slope T _J = 125 °C			50	V/ns	
Reverse Diode dV/dt ^d			dV/dt		
Soldering Recommendations (Peak Temperature) ^c	for	10 s		300	°C

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b. V_{DD} = 50 V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 3.5 A.

c. 1.6 mm from case. d. $I_{SD} \le I_D$, dl/dt = 100 A/µs, starting $T_J = 25$ °C.





JCS8N65FB-O-F-N-B

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THERMAL RESISTANCE RAT	INGS			
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	63	°C/W
Maximum Junction-to-Case (Drain)	Rth.IC	-	0.6	0/11

PARAMETER	SYMBOL	TES	T CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static				•	•	•	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	= 0 V, I _D = 250 μA	650	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA	-	0.65	-	V/°C
Gate-Source Threshold Voltage (N)	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μΑ	2.5	-	5	V
		,	V _{GS} = ± 20 V	-	-	± 100	nA
Gate-Source Leakage	I _{GSS}	,	$V_{GS} = \pm 30 \text{ V}$	-	-	± 1	μA
	V _{DS} = 650 V, V _{GS} = 0 V	-	-	1			
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 520 V	∕, V _{GS} = 0 V, T _J = 125 °C	-	-	10	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 4 A	-	1.1	-	Ω
Forward Transconductance	g _{fs}	V _{DS}	= 30 V, I _D = 4 A	-	16	-	S
Dynamic		•			1	I	1
Input Capacitance	C _{iss}	$V_{GS} = 0 V,$ $V_{DS} = 100 V,$ f = 1 MHz		-	860	-	-
Output Capacitance	C _{oss}			-	120	-	
Reverse Transfer Capacitance	C _{rss}			-	15	-	
Effective Output Capacitance, Energy Related ^a	C _{o(er)}			-	45	-	pF
Effective Output Capacitance, Time Related ^b	C _{o(tr)}	- V _{DS} = 0 V	/ to 520 V, V _{GS} = 0 V	-	62	-	
Total Gate Charge	Qg			-	25		
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 V$	$I_D = 4 \text{ A}, V_{DS} = 520 \text{ V}$	-	2.0	-	nC
Gate-Drain Charge	Q _{gd}			-	2.7	-]
Turn-On Delay Time	t _{d(on)}			-	25	-	
Rise Time	t _r			-	-		
Turn-Off Delay Time	t _{d(off)}		$= 10 \text{ V}, \text{ R}_{\text{g}} = 9.1 \Omega$	-	70	-	ns
Fall Time	t _f			-	40	-	
Gate Input Resistance	R _g	f = 1	MHz, open drain	-	3.5	-	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET syml showing the	MOSFET symbol showing the		-	7	
Pulsed Diode Forward Current	I _{SM}	integral revers p - n junction		-	-	18	A
Diode Forward Voltage	V _{SD}	T _J = 25 °	C, I _S = 4 A, V _{GS} = 0 V	-	-	1.5	V
Reverse Recovery Time	t _{rr}			-	190	-	ns
Reverse Recovery Charge	Q _{rr}	$T_J = 2$	$5 ^{\circ}\text{C}, I_{\text{F}} = I_{\text{S}} = 4 \text{A},$	-	2.3	-	μC
Reverse Recovery Current	I _{RRM}	ai/at =	100 A/µs, V _R = 400 V	_	10	-	A

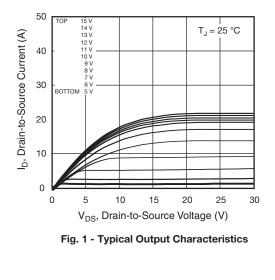
Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .

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TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



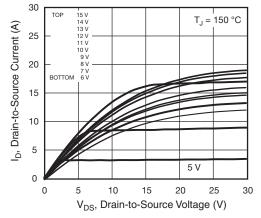


Fig. 2 - Typical Output Characteristics

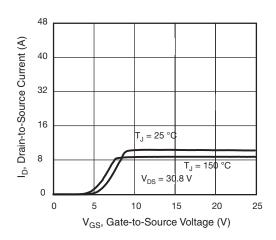


Fig. 3 - Typical Transfer Characteristics

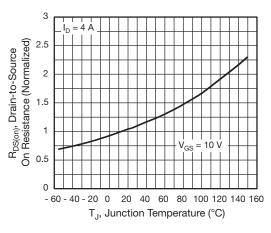


Fig. 4 - Normalized On-Resistance vs. Temperature

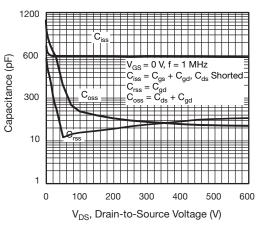


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

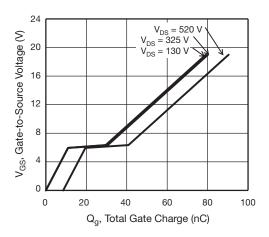


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

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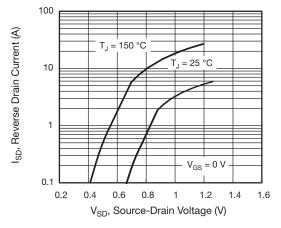


Fig. 7 - Typical Source-Drain Diode Forward Voltage

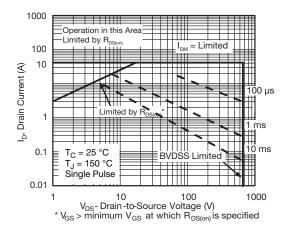


Fig. 8 - Maximum Safe Operating Area

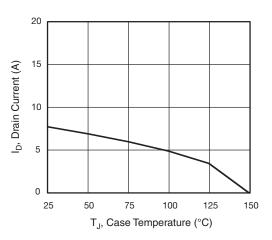


Fig. 9 - Maximum Drain Current vs. Case Temperature

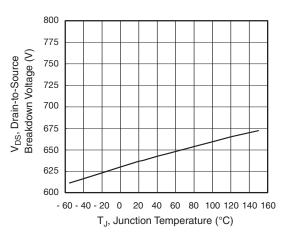


Fig. 10 - Temperature vs. Drain-to-Source Voltage

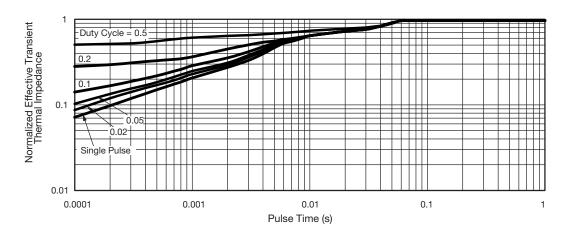


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



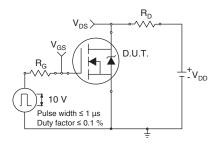


Fig. 12 - Switching Time Test Circuit

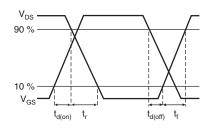


Fig. 13 - Switching Time Waveforms

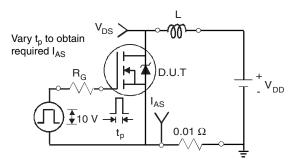


Fig. 14 - Unclamped Inductive Test Circuit

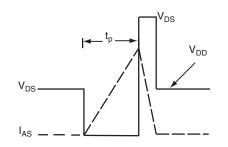


Fig. 15 - Unclamped Inductive Waveforms

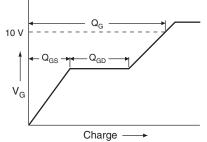


Fig. 16 - Basic Gate Charge Waveform

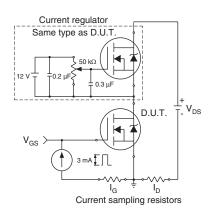
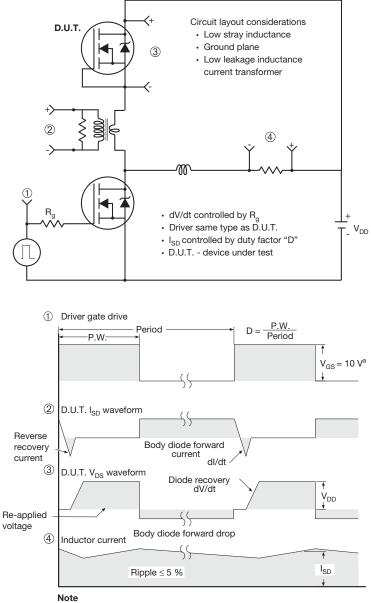


Fig. 17 - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

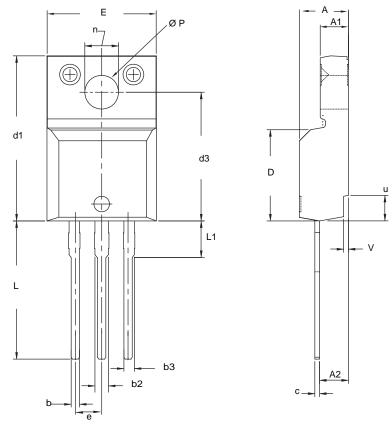


a. $V_{GS} = 5 V$ for logic level devices

Fig. 18 - For N-Channel



TO-220 FULLPAK (HIGH VOLTAGE)



	MILLI	METERS	INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
А	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
C	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
E	10.360	10.630	0.408	0.419
е	2.54	BSC	0.100) BSC
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
Ø P	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
V	0.400	0.500	0.016	0.020

Notes

1. To be used only for process drawing. 2. These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads. 3. All critical dimensions should C meet $C_{pk} > 1.33$. 4. All dimensions include burrs and plating thickness.

5. No chipping or package damage.



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